



# 16-BIT, 1.25-MSPS, UNIPOLAR PSEUDO-DIFFERENTIAL INPUT, MICROPOWER SAMPLING ANALOG-TO-DIGITAL CONVERTER WITH PARALLEL INTERFACE

### **FEATURES**

- Unipolar Pseudo-Differential Input, 0 V to V<sub>ref</sub>
- 16-Bit NMC at 1.25 MSPS
- ±2 LSB INL Max, -1/+1.5 LSB DNL
- 86 dB SNR, -90 dB THD at 100 kHz Input
- Zero Latency
- Internal 4.096-V Reference
- High-Speed Parallel Interface
- Single 5-V Analog Supply
- Wide I/O Supply: 2.7 V to 5.25 V
- Low Power: 155 mW at 1.25 MHz Typ
- Pin Compatible With ADS8411/8401
- 48-Pin TQFP Package

### **APPLICATIONS**

- DWDM
- Instrumentation
- High-Speed, High-Resolution, Zero Latency Data Acquisition Systems
- Transducer Interface
- Medical Instruments
- Communications

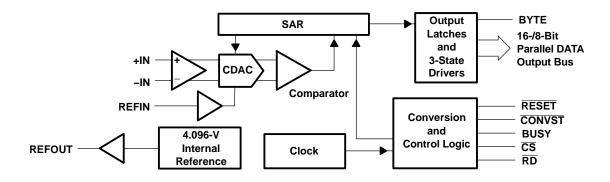
## **DESCRIPTION**

The ADS8405 is a 16-bit, 1.25-MHz A/D converter with an internal 4.096-V reference. The device includes a 16-bit capacitor-based SAR A/D converter with inherent sample and hold. The ADS8405 offers a full 16-bit interface and an 8-bit option where data is read using two 8-bit read cycles if necessary.

The ADS8405 has a unipolar pseudo-differential input. It is available in a 48-lead TQFP package and is characterized over the industrial -40°C to 85°C temperature range.

#### **High Speed SAR Converter Family**

					-			
Type/Speed	500 kHz	~600 kHz	750 kHz	1 MHz	1.25 MHz	2 MHz	3 MHz	4 MHz
40 D'' D	ADS8383	ADS8381						
18-Bit Pseudo-Diff		ADS8380 (S)						
18-Bit Pseudo-Bipolar, Fully Diff		ADS8382 (S)						
16-Bit Pseudo-Diff			ADS8371		ADS8401/05	ADS8411		
16-Bit Pseudo-Bipolar, Fully Diff					ADS8402/06	ADS8412		
14-Bit Pseudo-Diff					ADS7890 (S)		ADS7891	
12-Bit Pseudo-Diff				ADS7886				ADS7881





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



## ORDERING INFORMATION(1)

MODEL	MAXIMUM INTEGRAL LINEARITY (LSB)	MAXIMUM DIFFERENTIAL LINEARITY (LSB)	NO MISSING CODES RESOLUTION (BIT)	PACKAGE TYPE	PACKAGE DESIGNATOR	TEMPERATURE RANGE	ORDERING INFORMATION	TRANSPORT MEDIA QUANTITY
ADS8405I	-4 to +4	-2 to +2	15	48 Pin TQFP	PFB	–40°C to 85°C	ADS8405IPFBT	Tape and reel 250
AD364031	-4 10 +4	-2 10 +2	to +2 15 48	40 FIII IQFF	IQFF FFB	-40 C to 65 C	ADS8405IPFBR	Tape and reel 1000
ADS8405IB		445 445	48 Pin TQFP	PFB	-40°C to 85°C	ADS8405IBPFBT	Tape and reel 250	
AD36403IB	-2 10 +2	2 to +2	46 FIII 1QFF	FFB	-40 C to 65 C	ADS8405IBPFBR	Tape and reel 1000	

<sup>(1)</sup> For the most current specifications and package information, refer to our website at www.ti.com.

## **ABSOLUTE MAXIMUM RATINGS**

over operating free-air temperature range unless otherwise noted(1)

				UNIT
		+IN to AGNE	)	-0.4 V to +VA + 0.1 V
		-IN to AGNE	1	-0.4 V to 0.5 V
	Voltage	+VA to AGNI		–0.3 V to 7 V
		+VBD to BD0	GND	–0.3 V to 7 V
		+VA to +VBD	)	−0.3 V to 2.55 V
	Digital input volta	ge to BDGND		-0.3 V to +VBD + 0.3 V
	Digital output volt	age to BDGN	D	-0.3 V to +VBD + 0.3 V
T <sub>A</sub>	Operating free-ai	r temperature	range	-40°C to 85°C
T <sub>stg</sub>	Storage temperat	ture range		−65°C to 150°C
	Junction tempera	ture (T <sub>J</sub> max)		150°C
	TOED pookogo	Power dissip	ation	$(T_{J}Max - T_{A})/\theta_{JA}$
	TQFP package	$\theta_{JA}$ thermal in	mpedance	86°C/W
	Load tomporature	aaldarina	Vapor phase (60 sec)	215°C
	Lead temperature	e, soluering	Infrared (15 sec)	220°C

<sup>(1)</sup> Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



## **SPECIFICATIONS**

 $T_{A} = -40^{\circ}\text{C to } 85^{\circ}\text{C}, \text{ +VA} = 5 \text{ V}, \text{ +VBD} = 3 \text{ V or 5 V}, V_{ref} = 4.096 \text{ V}, f_{SAMPLE} = 1.25 \text{ MHz (unless otherwise noted)}$ 

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
ANALC	G INPUT					•	
	Full-scale input voltage (	1)	+IN - (-IN)	0		$V_{ref}$	V
	Alexander Samuel contract		+IN	-0.2		V <sub>ref</sub> + 0.2	
	Absolute input voltage		-IN	-0.2		0.2	V
	Input capacitance				25		pF
	Input leakage current				0.5		nA
SYSTE	M PERFORMANCE					1	
	Resolution				16		Bits
	No mineiro codos	ADS8405I		15			Dita
	No missing codes	ADS8405IB		16			Bits
		ADS8405I		-4	±2	4	1.00
INL	Integral linearity (2)(3)	ADS8405IB		-2	±1	2	LSB
D	<b>D</b> ''' (1.11)	ADS8405I		-2	±1	2	
DNL	Differential linearity	ADS8405IB		-1	±0.75	1.5	LSB
_	O" (4)	ADS8405I		-3	±1	3	mV
Eo	Offset error <sup>(4)</sup>	ADS8405IB		-1.5	±0.5	1.5	mV
	(1)(5)	ADS8405I		-0.15		0.15	
E <sub>G</sub> Gain error <sup>(4)(5)</sup>		ADS8405IB		-0.098		0.98	%FS
	Noise	11.			60		μV RM
	DC Power supply rejection	on ratio	At FFFFh output code, +VA = 4.75 V to 5.25 V, $V_{ref}$ = 4.096 $V^{(4)}$		2		LSB
SAMPL	ING DYNAMICS						
	Conversion time			500		650	ns
	Acquisition time			150			ns
	Throughput rate					1.25	MHz
	Aperture delay				2		ns
	Aperture jitter				25		ps
	Step response				100		ns
	Overvoltage recovery				100		ns
DYNAN	IIC CHARACTERISTICS					U.	
TUD	T	(6)	VIN = 4 V <sub>p-p</sub> at 100 kHz		-90		dB
THD	Total harmonic distortion	(6)	VIN = 4 V <sub>p-p</sub> at 500 kHz		-88.5		dB
SNR	Signal-to-noise ratio		$VIN = 4 V_{p-p}$ at 100 kHz		86		dB
SINAD			VIN = 4 V <sub>p-p</sub> at 100 kHz		85		dB
	<del>-</del>		VIN = 4 V <sub>p-p</sub> at 100 kHz		90		dB
SFDR	FDR Spurious free dynamic range		$VIN = 4 V_{p-p}$ at 500 kHz		88		dB
	-3dB Small signal bandw	ridth	77		5		MHz
EXTER	NAL VOLTAGE REFERE					J	
	Reference voltage at RE			2.5	4.096	4.2	V
	•	101					

<sup>(1)</sup> Ideal input span, does not include gain or offset error.

LSB means least significant bit

This is endpoint INL, not best fit.

Measured relative to an ideal full-scale input (+IN – (-IN)) of 4.096 V. This specification does not include the internal reference voltage error and drift.

Calculated on the first nine harmonics of the input frequency.

<sup>(6)</sup> (7) Can vary ±20%



# **SPECIFICATIONS** (continued)

 $T_A = -40$ °C to 85°C, +VA = 5 V, +VBD = 3 V or 5 V,  $V_{ref} = 4.096$  V,  $f_{SAMPLE} = 1.25$  MHz (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
INTER	NAL REFERENCE OUTPU	ΙΤ	·			<u> </u>	
			From 95% (+VA), with 1-µF storage capacitor			120	ms
	V <sub>ref</sub> range		IOUT = 0	4.065	4.096	4.13	V
	Source current		Static load			10	μΑ
	Line regulation		+VA = 4.75 V to 5.25 V		0.6		mV
	Drift		IOUT = 0		36		PPM/C
DIGITA	AL INPUT/OUTPUT						
	Logic family - CMOS						
$V_{IH}$	High-level input voltage		I <sub>IH</sub> = 5 μA	+VBD - 1	D – 1 +VBD + 0.3		
$V_{IL}$	Low-level input voltage		$I_{IL} = 5 \mu A$	-0.3		0.8	
$V_{OH}$	High-level output voltage		I <sub>OH</sub> = 2 TTL loads	+VBD - 0.6		+VBD V	
$V_{OL}$	Low-level output voltage		I <sub>OL</sub> = 2 TTL loads	0		0.4	
	Data format - straight bin	ary					
POWE	R SUPPLY REQUIREMEN	TS					
	Dower ounnly voltage	+VBD		2.7	3	5.25	V
	Power supply voltage	+VA		4.75	5	5.25	V
	+VA Supply current (8)		f <sub>s</sub> = 1.25 MHz		31	34	mA
	Power dissipation <sup>(8)</sup>		f <sub>s</sub> = 1.25 MHz		155	170	mW
TEMP	ERATURE RANGE					<u> </u>	
	Operating free-air			-40		85	°C

<sup>(8)</sup> This includes only VA+ current. +VBD current is typically 1 mA with 5-pF load capacitance on output pins.



## TIMING CHARACTERISTICS

All specifications typical at  $-40^{\circ}$ C to  $85^{\circ}$ C, +VA = +VBD = 5 V (1)(2)(3)

	PARAMETER	MIN	TYP MA	X UNI	IT
t <sub>CONV</sub>	Conversion time	500	65	0 ns	;
t <sub>ACQ</sub>	Acquisition time	150		ns	3
t <sub>pd1</sub>	CONVST low to BUSY high		40	ns	3
t <sub>pd2</sub>	Propagation delay time, end of conversion to BUSY low		5	ns	5
t <sub>w1</sub>	Pulse duration, CONVST low	20		ns	5
t <sub>su1</sub>	Setup time, CS low to CONVST low	0		ns	5
t <sub>w2</sub>	Pulse duration, CONVST high	20		ns	5
	CONVST falling edge jitter		1	0 ps	;
t <sub>w3</sub>	Pulse duration, BUSY signal low	Min(t <sub>ACQ</sub> )		ns	;
t <sub>w4</sub>	Pulse duration, BUSY signal high		610	ns	5
t <sub>h1</sub>	Hold time, first data bus data transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low	40		ns	<b>;</b>
t <sub>d1</sub>	Delay time, $\overline{CS}$ low to $\overline{RD}$ low (or BUSY low to $\overline{RD}$ low when $\overline{CS} = 0$ )	0		ns	\$
t <sub>su2</sub>	Setup time, RD high to CS high	0		ns	5
t <sub>w5</sub>	Pulse duration, RD low	50		ns	;
en	Enable time, $\overline{RD}$ low (or $\overline{CS}$ low for read cycle) to data valid		2	0 ns	;
t <sub>d2</sub>	Delay time, data hold from RD high	0		ns	;
t <sub>d3</sub>	Delay time, BYTE rising edge or falling edge to data valid	2	2	0 ns	3
t <sub>w6</sub>	Pulse duration, RD high	20		ns	;
t <sub>w7</sub>	Pulse duration, CS high	20		ns	;
t <sub>h2</sub>	Hold time, last $\overline{\text{RD}}$ (or $\overline{\text{CS}}$ for read cycle ) rising edge to $\overline{\text{CONVST}}$ falling edge	50		ns	;
t <sub>su3</sub>	Setup time, BYTE transition to RD falling edge	0		ns	5
t <sub>h3</sub>	Hold time, BYTE transition to RD falling edge	0		ns	;
dis	Disable time, RD high (CS high for read cycle) to 3-stated data bus		2	0 ns	;
d5	Delay time, end of conversion to MSB data valid		1	0 ns	;
t <sub>su4</sub>	Byte transition setup time, from BYTE transition to next BYTE transition	50		ns	3
d <sub>6</sub>	Delay time, CS rising edge to BUSY falling edge	50		ns	3
t <sub>d7</sub>	Delay time, BUSY falling edge to CS rising edge	50		ns	;
su(AB)	Setup time, from the falling edge of $\overline{\text{CONVST}}$ (used to start the valid conversion) to the next falling edge of $\overline{\text{CONVST}}$ (when $\overline{\text{CS}} = 0$ and $\overline{\text{CONVST}}$ used to abort) or to the next falling edge of $\overline{\text{CS}}$ (when $\overline{\text{CS}}$ is used to abort)	60	50	0 ns	<b>,</b>
t <sub>su5</sub>	Setup time, falling edge of CONVST to read valid data (MSB) from current conversion	$MAX(t_{CONV}) + MAX(t_{d5})$		ns	\$
t <sub>h4</sub>	Hold time, data (MSB) from previous conversion hold valid from falling edge of CONVST		MIN(t <sub>CON</sub>	ns	;

<sup>(1)</sup> All input signals are specified with  $t_r = t_f = 5$  ns (10% to 90% of +VBD) and timed from a voltage level of  $(V_{IL} + V_{IH})/2$ . (2) See timing diagrams.

<sup>(2)</sup> See timing diagrams.(3) All timings are measured with 20-pF equivalent loads on all data bits and BUSY pins.



## TIMING CHARACTERISTICS

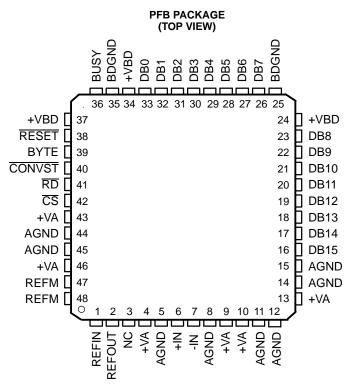
All specifications typical at  $-40^{\circ}$ C to  $85^{\circ}$ C, +VA = 5 V, +VBD = 3 V<sup>(1)(2)(3)</sup>

	PARAMETER	MIN	TYP MAX	UNIT
t <sub>CONV</sub>	Conversion time	500	650	ns
t <sub>ACQ</sub>	Acquisition time	150		ns
t <sub>pd1</sub>	CONVST low to BUSY high		50	ns
t <sub>pd2</sub>	Propagation delay time, end of conversion to BUSY low		10	ns
t <sub>w1</sub>	Pulse duration, CONVST low	20		ns
t <sub>su1</sub>	Setup time, $\overline{\text{CS}}$ low to $\overline{\text{CONVST}}$ low	0		ns
t <sub>w2</sub>	Pulse duration, CONVST high	20		ns
	CONVST falling edge jitter		10	ps
t <sub>w3</sub>	Pulse duration, BUSY signal low	Min(t <sub>ACQ</sub> )		ns
t <sub>w4</sub>	Pulse duration, BUSY signal high		610	ns
t <sub>h1</sub>	Hold time, first data bus transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low	40		ns
t <sub>d1</sub>	Delay time, $\overline{CS}$ low to $\overline{RD}$ low (or BUSY low to $\overline{RD}$ low when $\overline{CS} = 0$ )	0		ns
t <sub>su2</sub>	Setup time, RD high to CS high	0		ns
t <sub>w5</sub>	Pulse duration, RD low	50		ns
t <sub>en</sub>	Enable time, RD low (or CS low for read cycle) to data valid		30	ns
t <sub>d2</sub>	Delay time, data hold from RD high	0		ns
t <sub>d3</sub>	Delay time, BYTE rising edge or falling edge to data valid	2	30	ns
t <sub>w6</sub>	Pulse duration, RD high	20		ns
t <sub>w7</sub>	Pulse duration, CS high	20		ns
t <sub>h2</sub>	Hold time, last $\overline{\text{RD}}$ (or $\overline{\text{CS}}$ for read cycle ) rising edge to $\overline{\text{CONVST}}$ falling edge	50		ns
t <sub>su3</sub>	Setup time, BYTE transition to RD falling edge	0		ns
t <sub>h3</sub>	Hold time, BYTE transition to RD falling edge	0		ns
t <sub>dis</sub>	Disable time, RD high (CS high for read cycle) to 3-stated data bus		30	ns
t <sub>d5</sub>	Delay time, end of conversion to MSB data valid		20	ns
t <sub>su4</sub>	Byte transition setup time, from BYTE transition to next BYTE transition	50		ns
t <sub>d6</sub>	Delay time, CS rising edge to BUSY falling edge	50		ns
t <sub>d7</sub>	Delay time, BUSY falling edge to CS rising edge	50		ns
t <sub>su(AB)</sub>	Setup time, from the falling edge of $\overline{\text{CONVST}}$ (used to start the valid conversion) to the next falling edge of $\overline{\text{CONVST}}$ (when $\overline{\text{CS}} = 0$ and $\overline{\text{CONVST}}$ used to abort) or to the next falling edge of $\overline{\text{CS}}$ (when $\overline{\text{CS}}$ is used to abort)	70	500	ns
t <sub>su5</sub>	Setup time, falling edge of CONVST to read valid data (MSB) from current conversion	$MAX(t_{CONV}) + MAX(t_{d5})$		ns
t <sub>h4</sub>	Hold time, data (MSB) from previous conversion hold valid from falling edge of CONVST		MIN(t <sub>CONV</sub> )	ns

 <sup>(1)</sup> All input signals are specified with t<sub>r</sub> = t<sub>f</sub> = 5 ns (10% to 90% of +VBD) and timed from a voltage level of (V<sub>IL</sub> + V<sub>IH</sub>)/2.
 (2) See timing diagrams.
 (3) All timings are measured with 10-pF equivalent loads on all data bits and BUSY pins.



## **PIN ASSIGNMENTS**



NC - No connection

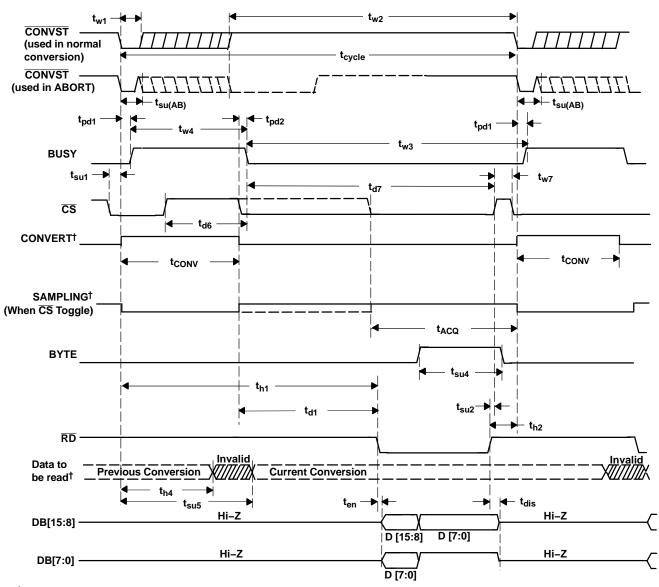


## **Terminal Functions**

NAME	NO.	I/O		DESCRIPTION			
AGND	5, 8, 11, 12, 14, 15, 44, 45	-	Analog ground				
BDGND	25, 35	-	Digital ground for bus interface	digital supply			
BUSY	36	0	Status output. High when a co	nversion is in progress.			
BYTE	39	I	Byte select input. Used for 8-b significant bits is folded back to		ck 1: Low byte D[7:0] of the 16 most gnificant pins DB[15:8].		
CONVST	40	I	Convert start. The falling edge period.	of this input ends the acquis	sition period and starts the hold		
CS	42	I	Chip select. The falling edge of	f this input starts the acquisi	tion period.		
Data Dua			8-Bit E	lus	16-Bit Bus		
Data Bus			BYTE = 0	BYTE = 1	BYTE = 0		
DB15	16	0	D15 (MSB)	D7	D15 (MSB)		
DB14	17	0	D14	D6	D14		
DB13	18	0	D13	D5	D13		
DB12	19	0	D12	D4	D12		
DB11	20	0	D11	D3	D11		
DB10	21	0	D10	D2	D10		
DB9	22	0	D9	D1	D9		
DB8	23	0	D8	D0 (LSB)	D8		
DB7	26	0	D7	All ones	D7		
DB6	27	0	D6	All ones	D6		
DB5	28	0	D5	All ones	D5		
DB4	29	0	D4	All ones	D4		
DB3	30	0	D3	All ones	D3		
DB2	31	0	D2	All ones	D2		
DB1	32	0	D1	All ones	D1		
DB0	33	0	D0 (LSB)	All ones	D0 (LSB)		
-IN	7	I	Inverting input channel	<u>'</u>			
+IN	6	I	Noninverting input channel				
NC	3	_	No connection				
REFIN	1	I	Reference input				
REFM	47, 48	I	Reference ground				
REFOUT	2	0	Reference output. Add 1-µF capacitor between the REFOUT pin and REFM pin when the internal reference is used.				
RESET	38	I	Current conversion is aborted and output latches are cleared (set to zeros) when this pin is asserted low. RESET works independently of CS.				
RD	41	I	Synchronization pulse for the parallel output. When $\overline{\text{CS}}$ is low, this serves as the output enable and puts the previous conversion result on the bus.				
+VA	4, 9, 10, 13, 43, 46	-	Analog power supplies, 5-V do				
+VBD	24, 34, 37	-	Digital power supply for bus				



## **TIMING DIAGRAMS**



<sup>†</sup>Signal internal to device

Figure 1. Timing for Conversion and Acquisition Cycles With CS and RD Toggling



## **TIMING DIAGRAMS (continued)**

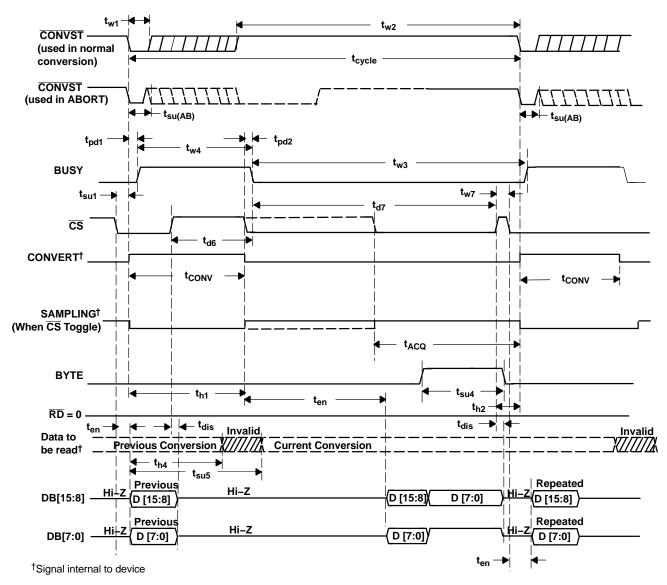


Figure 2. Timing for Conversion and Acquisition Cycles With  $\overline{\text{CS}}$  Toggling,  $\overline{\text{RD}}$  Tied to BDGND



## **TIMING DIAGRAMS (continued)**

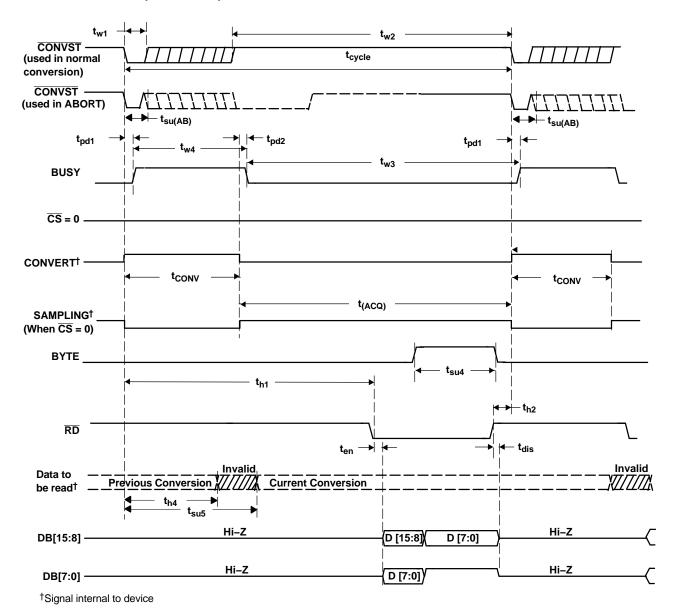
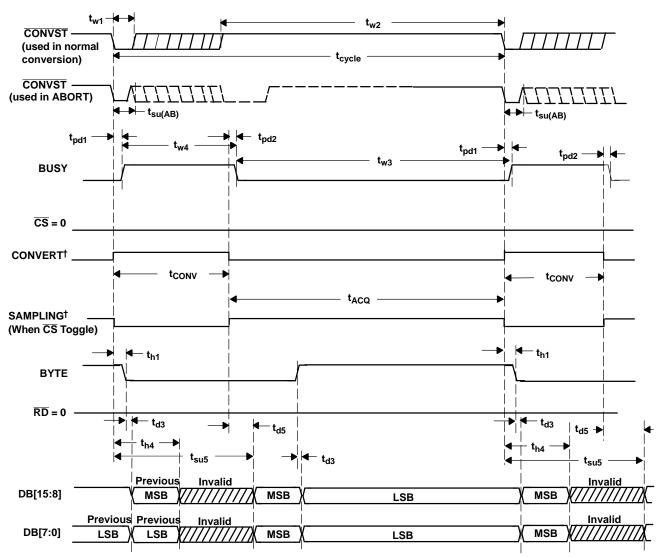


Figure 3. Timing for Conversion and Acquisition Cycles With  $\overline{\text{CS}}$  Tied to BDGND,  $\overline{\text{RD}}$  Toggling



## **TIMING DIAGRAMS (continued)**



<sup>†</sup>Signal internal to device

Figure 4. Timing for Conversion and Acquisition Cycles With  $\overline{\text{CS}}$  and  $\overline{\text{RD}}$  Tied to BDGND—Auto Read

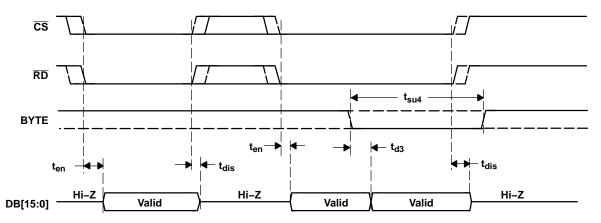


Figure 5. Detailed Timing for Read Cycles



### TYPICAL CHARACTERISTICS

At  $-40^{\circ}$ C to  $85^{\circ}$ C, +VA = 5 V, +VBD = 5 V, REFIN = 4.096 V (internal reference used) and  $f_{sample}$  = 1.25 MHz (unless otherwise noted)

# HISTOGRAM (DC Code Spread) HALF SCALE 131071 CONVERSIONS

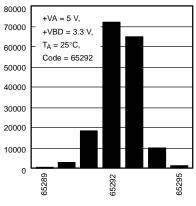


Figure 6.

# SIGNAL-TO-NOISE AND DISTORTION vs FREE-AIR TEMPERATURE

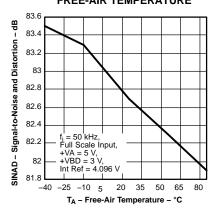


Figure 8.

#### SIGNAL-TO-NOISE RATIO vs FREE-AIR TEMPERATURE

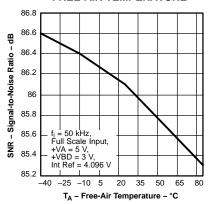


Figure 7.

# EFFECTIVE NUMBER OF BITS vs FREE-AIR TEMPERATURE

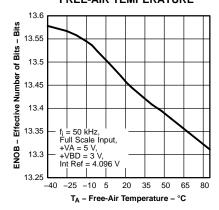


Figure 9.



# SPURIOUS FREE DYNAMIC RANGE vs FREE-AIR TEMPERATURE

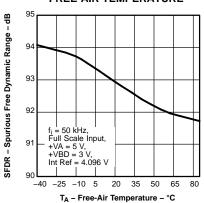


Figure 10.

# SIGNAL-TO-NOISE RATIO VS INPUT FREQUENCY

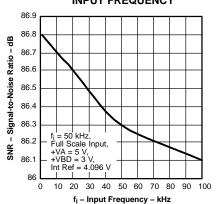


Figure 12.

# SIGNAL-TO-NOISE AND DISTORTION VS INPUT FREQUENCY

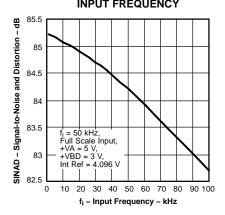


Figure 14.

# TOTAL HARMONIC DISTORTION vs FREE-AIR TEMPERATURE

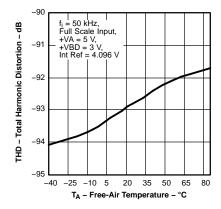


Figure 11.

# EFFECTIVE NUMBER OF BITS VS INPUT FREQUENCY

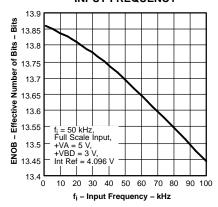


Figure 13.

# SPURIOUS FREE DYNAMIC RANGE VS INPUT FREQUENCY

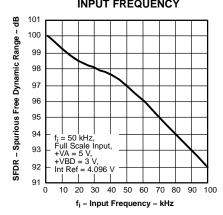


Figure 15.



# TOTAL HARMONIC DISTORTION VS INPUT FREQUENCY

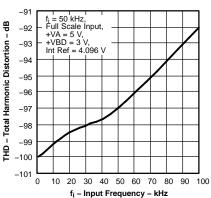


Figure 16.

#### GAIN ERROR vs SUPPLY VOLTAGE

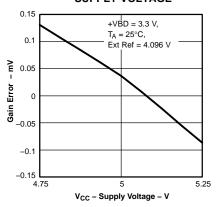


Figure 18.

#### INTERNAL VOLTAGE REFERENCE vs FREE-AIR TEMPERATURE

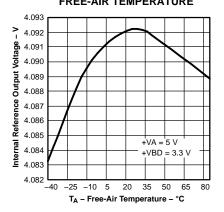


Figure 20.

#### SUPPLY CURRENT vs SAMPLE RATE

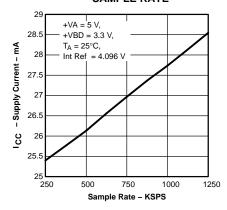


Figure 17.

#### OFFSET ERROR VS SUPPLY VOLTAGE

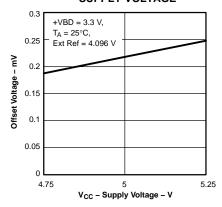


Figure 19.

#### GAIN ERROR vs FREE-AIR TEMPERATURE

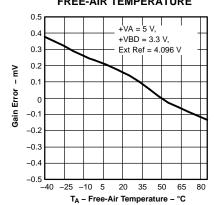


Figure 21.



#### OFFSET ERROR vs FREE-AIR TEMPERATURE

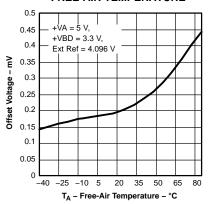


Figure 22.

# DIFFERENTIAL NONLINEARITY vs FREE-AIR TEMPERATURE

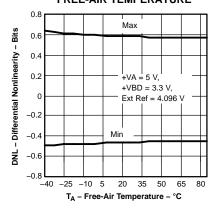


Figure 24.

# DIFFERENTIAL NONLINEARITY VS REFERENCE VOLTAGE

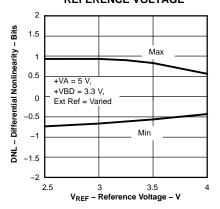


Figure 26.

#### SUPPLY CURRENT vs FREE-AIR TEMPERATURE

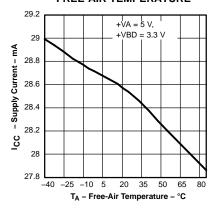


Figure 23.

# INTEGRAL NONLINEARITY vs FREE-AIR TEMPERATURE

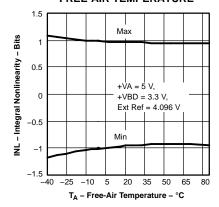


Figure 25.

# INTEGRAL NONLINEARITY vs REFERENCE VOLTAGE

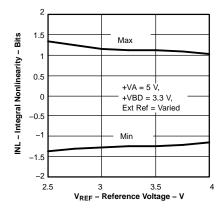
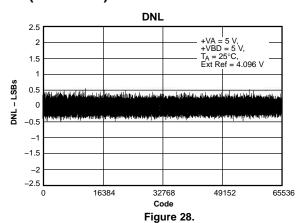


Figure 27.





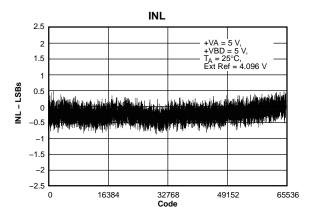
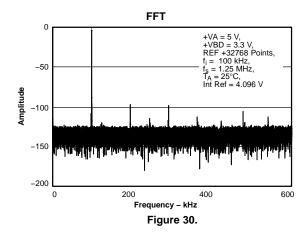


Figure 29.





### **APPLICATION INFORMATION**

#### MICROCONTROLLER INTERFACING

### ADS8405 to 8-Bit Microcontroller Interface

Figure 31 shows a parallel interface between the ADS8405 and a typical microcontroller using the 8-bit data bus. The BUSY signal is used as a falling-edge interrupt to the microcontroller.

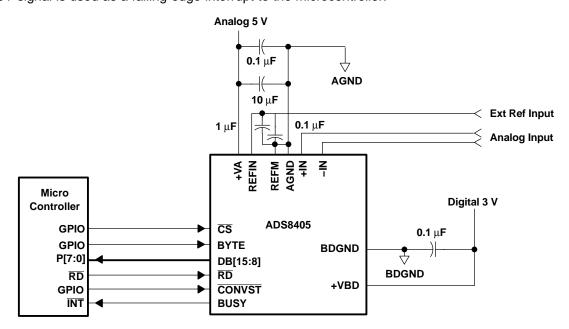


Figure 31. ADS8405 Application Circuitry (Using an External Reference)

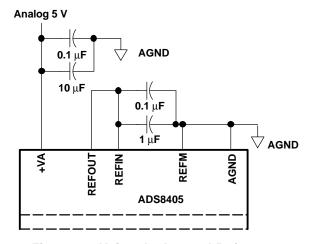


Figure 32. Using the Internal Reference

### PRINCIPLES OF OPERATION

The ADS8405 is a high-speed successive approximation register (SAR) analog-to-digital converter (ADC). The architecture is based on charge redistribution, which inherently includes a sample/hold function. See Figure 31 for the application circuit for the ADS8405.

The conversion clock is generated internally. The conversion time of 650 ns is capable of sustaining a 1.25-MHz throughput.



## PRINCIPLES OF OPERATION (continued)

The analog input is provided to two input pins: +IN and -IN. When a conversion is initiated, the differential input on these pins is sampled on the internal capacitor array. While a conversion is in progress, both inputs are disconnected from any internal function.

### REFERENCE

The ADS8405 can operate with an external reference with a range from 2.5 V to 4.2 V. A 4.096-V internal reference is included. When an internal reference is used, pin 2 (REFOUT) should be connected to pin 1 (REFIN) with a 0.1-µF decoupling capacitor and a 1-µF storage capacitor between pin 2 (REFOUT) and pins 47 and 48 (REFM) (see Figure 32). The internal reference of the converter is double buffered. If an external reference is used, the second buffer provides isolation between the external reference and the CDAC. This buffer is also used to recharge all of the capacitors of the CDAC during conversion. Pin 2 (REFOUT) can be left unconnected (floating) if an external reference is used.

## **ANALOG INPUT**

When the converter enters hold mode, the voltage difference between the +IN and -IN inputs is captured on the internal capacitor array. The voltage on the -IN input is limited between -0.2 V and 0.2 V, allowing the input to reject small signals which are common to both the +IN and -IN inputs. The +IN input has a range of -0.2 V to  $V_{ref}$  + 0.2 V. The input span (+IN - (-IN)) is limited to 0 V to  $V_{ref}$ .

The input current on the analog inputs depends upon a number of factors: sample rate, input voltage, and source impedance. Essentially, the current into the ADS8405 charges the internal capacitor array during the sample period. After this capacitance has been fully charged, there is no further input current. The source of the analog input voltage must be able to charge the input capacitance (25 pF) to an 16-bit settling level within the acquisition time (150 ns) of the device. When the converter goes into hold mode, the input impedance is greater than 1 G $\Omega$ .

Care must be taken regarding the absolute analog input voltage. To maintain the linearity of the converter, the +IN and -IN inputs and the span (+IN - (-IN)) should be within the limits specified. Outside of these ranges, the converter's linearity may not meet specifications. To minimize noise, low bandwidth input signals with low-pass filters should be used.

Care should be taken to ensure that the output impedance of the sources driving the +IN and -IN inputs are matched. If this is not observed, the two inputs could have different setting times. This may result in offset error, gain error, and linearity error which varies with temperature and input voltage. A typical input circuit using TI's THS4031 is shown in Figure 33.

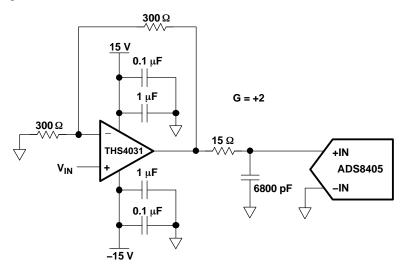


Figure 33. Using the THS4031 with the ADS8405



# PRINCIPLES OF OPERATION (continued) DIGITAL INTERFACE

### **Timing And Control**

See the timing diagrams in the specifications section for detailed information on timing signals and their requirements.

The ADS8405 uses an internal oscillator generated clock which controls the conversion rate and in turn the throughput of the converter. No external clock input is required.

Conversions are initiated by bringing the  $\overline{\text{CONVST}}$  pin low for a minimum of 20 ns (after the 20 ns minimum requirement has been met, the  $\overline{\text{CONVST}}$  pin can be brought high) while  $\overline{\text{CS}}$  is low. The ADS8405 switches from the sample to the hold mode on the falling edge of the  $\overline{\text{CONVST}}$  command. A clean and low jitter falling edge of this signal is important to the performance of the converter. The BUSY output is brought high after  $\overline{\text{CONVST}}$  goes low. BUSY stays high throughout the conversion process and returns low when the conversion has ended.

Sampling starts as soon as the conversion is over when  $\overline{CS}$  is tied low or starts with the falling edge of  $\overline{CS}$  when BUSY is low.

Both  $\overline{RD}$  and  $\overline{CS}$  can be high during and before a conversion with one exception ( $\overline{CS}$  must be low when  $\overline{CONVST}$  goes low to initiate a conversion). Both the  $\overline{RD}$  and  $\overline{CS}$  pins are brought low in order to enable the parallel output bus with the conversion.

## **Reading Data**

The ADS8405 outputs full parallel data in straight binary format as shown in Table 1. The parallel output is active when  $\overline{CS}$  and  $\overline{RD}$  are both low. There is a minimal quiet zone requirement around the falling edge of  $\overline{CONVST}$ . This is 50 ns prior to the falling edge of  $\overline{CONVST}$  and 40 ns after the falling edge. No data read should be attempted within this zone. Any other combination of  $\overline{CS}$  and  $\overline{RD}$  sets the parallel output to 3-state. BYTE is used for multiword read operations. BYTE is used whenever lower bits of the converter result are output on the higher byte of the bus. Refer to Table 1 for ideal output codes.

**DESCRIPTION ANALOG VALUE DIGITAL OUTPUT** Full scale range +V<sub>ref</sub> STRAIGHT BINARY (+V<sub>ref</sub>)/65536 Least significant bit (LSB) **BINARY CODE HEX CODE** Full scale  $(+V_{ref}) - 1 LSB$ 1111 1111 1111 1111 **FFFF** 1000 0000 0000 0000 Midscale (+V<sub>ref</sub>)/2 8000 Midscale - 1 LSB  $(+V_{ref})/2 - 1 LSB$ 0111 1111 1111 1111 7FFF 0 V 0000 0000 0000 0000 0000

**Table 1. Ideal Input Voltages and Output Codes** 

The output data is a full 16-bit word (D15 – D0) on the DB15 – DB0 pins (MSB-LSB) if BYTE is low.

The result may also be read on an 8-bit bus for convenience. This is done by using only pins DB15 – DB8. In this case two reads are necessary: the first as before, leaving BYTE low and reading the 8 most significant bits on pins DB15 – DB8, then bringing BYTE high. When BYTE is high, the low bits (D7 – D0) appear on pins DB15 – D8.

These multiword read operations can be done with multiple active RD (toggling) or with RD tied low for simplicity.

#### Conversion Data Readout

BYTE	DATA READ OUT					
	DB15-DB8 Pins	DB7-DB0 Pins				
High	D7-D0	All one's				
Low	D15-D8	D7-D0				



#### RESET

RESET is an asynchronous active low input signal (that works independently of  $\overline{CS}$ ). Minimum  $\overline{RESET}$  low time is 25 ns. The current conversion is aborted no later than 50 ns after the converter is in reset mode. In addition, all output latches are cleared (set to zero's) after  $\overline{RESET}$ . The converter goes back to normal operation mode no later than 20 ns after the  $\overline{RESET}$  input is brought high.

The converter starts the first sampling period 20 ns after the rising edge of RESET. Any sampling period except for the one immediately after a RESET is started with the falling edge of the previous BUSY signal or the falling edge of CS, whichever is later.

Another way to reset the device is through the use of the combination of  $\overline{CS}$  and  $\overline{CONVST}$ . This is useful when the dedicated  $\overline{RESET}$  pin is tied to the system reset but there is a need to abort only the conversion in a specific converter. Since the BUSY signal is held high during the conversion, either one of these conditions triggers an internal self-clear reset to the converter just the same as a reset via the dedicated  $\overline{RESET}$  pin. The reset does not have to be cleared as for the dedicated  $\overline{RESET}$  pin. A reset can be started with either of the two following steps.

- Issue a CONVST when CS is low and a conversion is in progress. The falling edge of CONVST must satisfy
  the timing as specified by the timing parameter t<sub>su(AB)</sub> specified in the timing characteristics table to ensure a
  reset. The falling edge of CONVST starts a reset. The timing is the same as a reset using the dedicated
  RESET pin except the instance of the falling edge is replaced by the falling edge of CONVST.
- Issue a S while a conversion is in progress. The falling edge of S must satisfy the timing as specified by the timing parameter t<sub>su(AB)</sub> specified in the timing characteristics table to ensure a reset. The falling edge of S causes a reset. The timing is the same as a reset using the dedicated ESET pin except the instance of the falling edge is replaced by the falling edge of S.

### **POWER-ON INITIALIZATION**

RESET is not required after power on. An internal power-on reset circuit generates the reset. To ensure that all of the registers are cleared, the three conversion cycles must be given to the converter after power on.

### **LAYOUT**

For optimum performance, care should be taken with the physical layout of the ADS8405 circuitry.

As the ADS8405 offers single-supply operation, it is often used in close proximity with digital logic, microcontrollers, microprocessors, and digital signal processors. The more digital logic present in the design and the higher the switching speed, the more difficult it is to achieve good performance from the converter.

The basic SAR architecture is sensitive to glitches or sudden changes on the power supply, reference, ground connections, and digital inputs that occur just prior to latching the output of the analog comparator. Thus, driving any single conversion for an n-bit SAR converter, there are at least n *windows* in which large external transient voltages can affect the conversion result. Such glitches might originate from switching power supplies, nearby digital logic, or high power devices.

The degree of error in the digital output depends on the reference voltage, layout, and the exact timing of the external event.

On average, the ADS8405 draws very little current from an external reference, as the reference voltage is internally buffered. If the reference voltage is external and originates from an op amp, make sure that it can drive the bypass capacitor or capacitors without oscillation. A 0.1-µF bypass capacitor and a 1-µF storage capacitor are recommended from pin 1 (REFIN) directly to pin 48 (REFM). REFM and AGND should be shorted on the same ground plane under the device.

The AGND and BDGND pins should be connected to a clean ground point. In all cases, this should be the analog ground. Avoid connections which are close to the grounding point of a microcontroller or digital signal processor. If required, run a ground trace directly from the converter to the power supply entry point. The ideal layout consists of an analog ground plane dedicated to the converter and associated analog circuitry.



As with the AGND connections, +VA should be connected to a 5-V power supply plane or trace that is separate from the connection for digital logic until they are connected at the power entry point. Power to the ADS8405 should be clean and well bypassed. A 0.1-µF ceramic bypass capacitor should be placed as close to the device as possible. See Table 2 for the placement of the capacitor. In addition, a 1-µF to 10-µF capacitor is recommended. In some situations, additional bypassing may be required, such as a 100-µF electrolytic capacitor or even a Pi filter made up of inductors and capacitors—all designed to essentially low-pass filter the 5-V supply, removing the high frequency noise.

**Table 2. Power Supply Decoupling Capacitor Placement** 

POWER SUPPLY PLANE SUPPLY PINS	CONVERTER ANALOG SIDE	CONVERTER DIGITAL SIDE
Pin pairs that require shortest path to decoupling capacitors	(4,5), (8,9), (10,11), (13,15), (43,44), (45,46)	(24,25), (34, 35)
Pins that require no decoupling	12, 14	37

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### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	<b>RoHS</b> (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
ADS8405IBPFBR	Active	Production	TQFP (PFB)   48	1000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	ADS8405I B
ADS8405IBPFBR.B	Active	Production	TQFP (PFB)   48	1000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	ADS8405I B
ADS8405IBPFBT	Active	Production	TQFP (PFB)   48	250   SMALL T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	ADS8405I B
ADS8405IBPFBT.B	Active	Production	TQFP (PFB)   48	250   SMALL T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	ADS8405I B
ADS8405IBPFBTG4	Active	Production	TQFP (PFB)   48	250   SMALL T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	ADS8405I B
ADS8405IPFBR	Active	Production	TQFP (PFB)   48	1000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	ADS8405I
ADS8405IPFBR.B	Active	Production	TQFP (PFB)   48	1000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	ADS8405I
ADS8405IPFBT	Active	Production	TQFP (PFB)   48	250   SMALL T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	ADS8405I
ADS8405IPFBT.B	Active	Production	TQFP (PFB)   48	250   SMALL T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	ADS8405I

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



## PACKAGE OPTION ADDENDUM

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# **PACKAGE MATERIALS INFORMATION**

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## TAPE AND REEL INFORMATION





	-
A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	_	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ADS8405IBPFBR	TQFP	PFB	48	1000	330.0	16.4	9.6	9.6	1.5	12.0	16.0	Q2
ADS8405IPFBR	TQFP	PFB	48	1000	330.0	16.4	9.6	9.6	1.5	12.0	16.0	Q2



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### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ADS8405IBPFBR	TQFP	PFB	48	1000	350.0	350.0	43.0
ADS8405IPFBR	TQFP	PFB	48	1000	350.0	350.0	43.0



PLASTIC QUAD FLATPACK



### NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
   This drawing is subject to change without notice.
   Reference JEDEC registration MS-026.



PLASTIC QUAD FLATPACK



NOTES: (continued)

- 4. Publication IPC-7351 may have alternate designs.
- 5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



PLASTIC QUAD FLATPACK



NOTES: (continued)



<sup>6.</sup> Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

<sup>7.</sup> Board assembly site may have different recommendations for stencil design.

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